MAPS REC'S PUT/PTO 08 DEC 2005

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			U.S	. PATENT DOCUMENTS	, 2005			
*EXAMINER	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	: FILING I	1
WB		6,879,167	4/12/05	JU ET AL.	G01R	27/04	IF APPROI	PRIATE
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			U.S. PATEN	F APPLICATION PUBLICATIONS				
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			FORE	IGN PATENT DOCUMENTS			· · ·	
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Transi YES	ntion NO
WB		61-173171	04.08.1986	JAPAN (w/abstract)	G01R	27/02	:	1
WB		09-021837	21.01.1997	JAPAN (w/abstract)	G01R	27/02		✓.
WB		2004-177274	24.06.2004	JAPAN (w/abstract)	G01R	27/02		. 1
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WB		"Contactless measure al., Journal of Applie	ement of electrical of Physics Letters,	conductivity of semiconductor wa Vol. 81n19, 2002, pp. 3585-3587.	fers using the ref	lection of milli	meter wave:	s", Ju et
EXAMINER /Wa			/Walter Bens	on/ DATE CONSIDERED 05/23/2006				
EXAMINE	R: Ini	tial if citation considered, wheth nclude copy of this form with n	ner or not citation is in	n conformance with MPEP Section 6 applicant.	09; Draw line thro	ugh citation if no	t in conform	ance and